


Search Notes 	Application/Control No. 10578686	Applicant(s)/Patent Under Reexamination YAMANAKA ET AL.
	Examiner JAYESH PATEL	Art Unit 2624

SEARCHED

Class	Subclass	Date	Examiner
382	300	08/26/2009	JP

SEARCH NOTES

Search Notes	Date	Examiner
See attached East, IEEE and inventor search	08/26/2009	JP
See the updated East, IEEE and the inventor search. Consulted with SPE Samir regarding the allowance. (Interpolat\$3 and (averag\$3 or mean) and (sequence or line or ((linear adj array) near10 (pixels or pels))))).clm. for interference	2/2/2010	JP

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
382	300	2/4/2010	JP

/J. P./
Examiner, Art Unit 2624